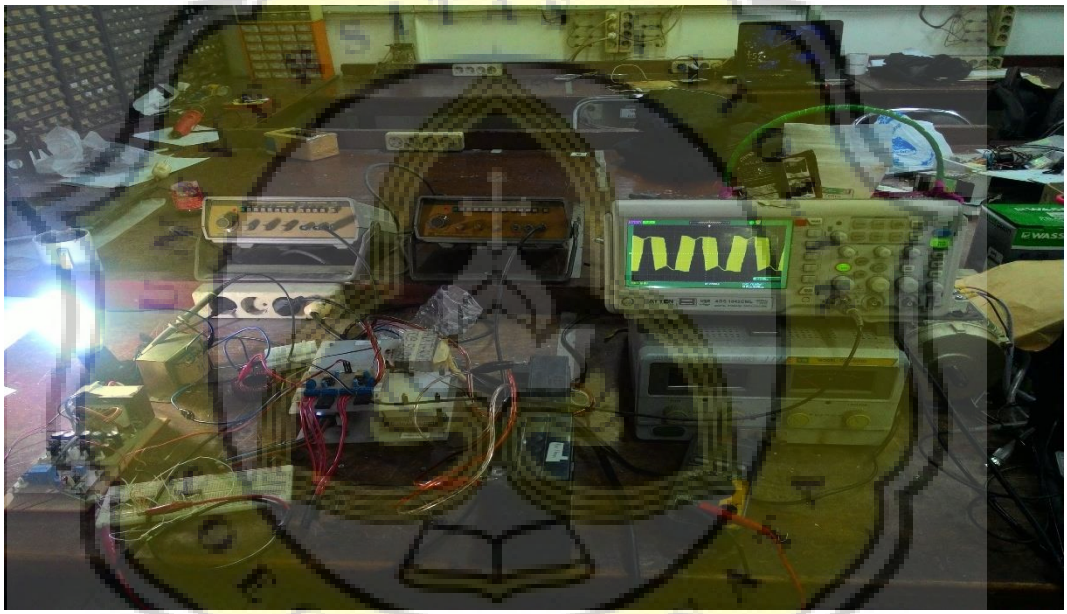
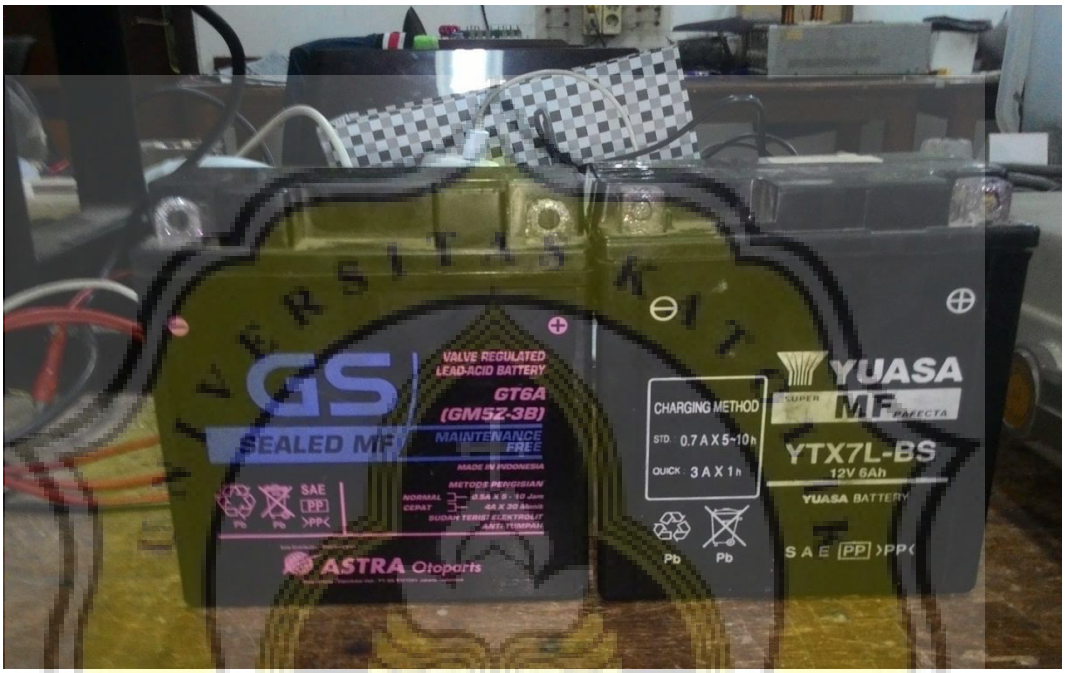
8. Y. Swidyatmoko, 2010, *Pemanfaatan Mikrokontroller ATMEGA8535 sebagai Pengendali inverter satu fasa jembatan PenuhTerprogram ¼ λ*, TugasAkhir, UniversitasKatolikSoegijapranata, Semarang.

Lampiran

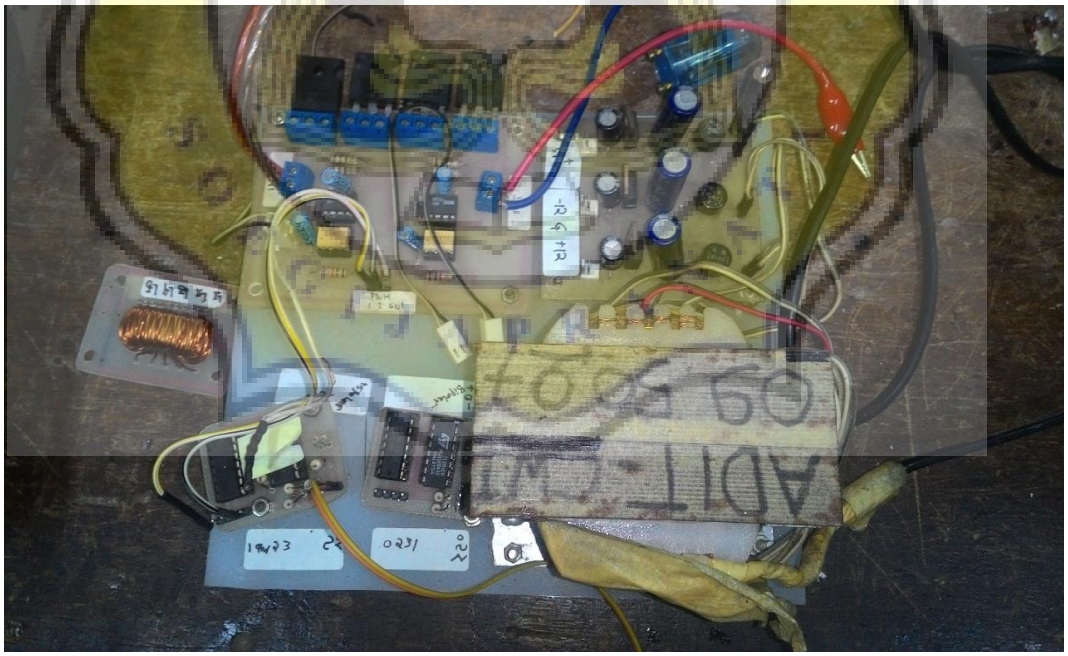


Alat studi komparasi inverter satu fasa dengan strategi unipolar dan bipolar dengan beban lampu


GS
SEALED MF
VALVE REGULATED
LEAD-ACID BATTERY
GT6A
(GM5Z-3B)
MAINTENANCE
FREE
ASTRA Otoparts
CHARGING METHOD
STD. 0.7 A X 5~10 h
QUICK 3 A X 1 h
YUASA
MF
YTX7L-BS
12V 6Ah
YUASA BATTERY
Pb
Pb

Baterai

Audio Function Generator (AFG)



Alat studi komparasi inverter satu fasa dengan strategi unipolar dan bipolar

Data sheet TLP 250

TOSHIBA Photocoupler GaAlAs Ired & Photo-IC

TLP250

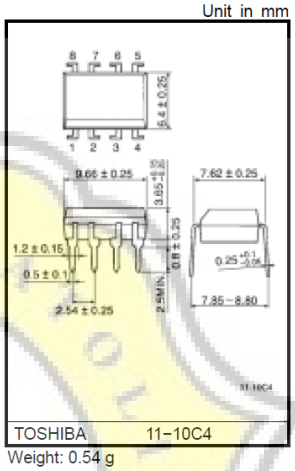
Transistor Inverter
Inverter For Air Conditionor
IGBT Gate Drive
Power MOS FET Gate Drive

The TOSHIBA TLP250 consists of a GaAlAs light emitting diode and a integrated photodetector.
This unit is 8-lead DIP package.
TLP250 is suitable for gate driving circuit of IGBT or power MOS FET.

- Input threshold current: I_F=5mA(max.)
- Supply current (I_{CC}): 11mA(max.)
- Supply voltage (V_{CC}): 10-35V
- Output current (I_O): ±1.5A (max.)
- Switching time (t_{pLH}/t_{pHL}): 1.5μs(max.)
- Isolation voltage: 2500V_{rms}(min.)
- UL recognized: UL1577, file No.E67349
- Option (D4) type
  VDE approved: DIN VDE0884/06.92,certificate No.76823
  Maximum operating insulation voltage: 630V_{PK}
  Highest permissible over voltage: 4000V_{PK}

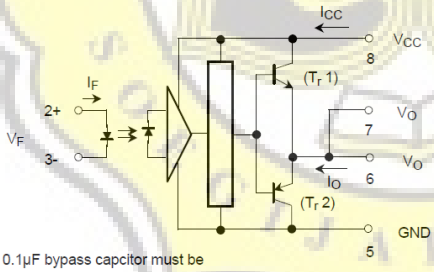
  (Note) When a VDE0884 approved type is needed, please designate the "option (D4)"
- Creepage distance: 6.4mm(min.)
  Clearance: 6.4mm(min.)

Unit in mm



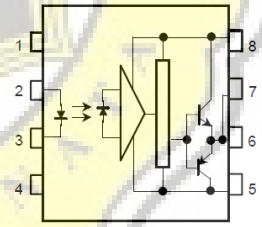
Weight: 0.54 g

Schmatic



A 0.1μF bypass capcitor must be connected between pin 8 and 5 (See Note 5).

Pin Configuration (top view)



1 : N.C.
2 : Anode
3 : Cathode
4 : N.C.
5 : GND
6 : V_O (Output)
7 : V_O
8 : V_{CC}

Truth Table

		Tr1	Tr2
Input LED	On	On	Off
	Off	Off	On

Absolute Maximum Ratings (Ta = 25°C)

	Characteristic		Symbol	Rating	Unit
LED	Forward current		I_F	20	mA
	Forward current derating (Ta ≥ 70°C)		$\Delta I_F / \Delta Ta$	−0.36	mA / °C
	Peak transient forward curent	(Note 1)	I_{FPT}	1	A
	Reverse voltage		V_R	5	V
	Junction temperature		Tj	125	°C
Detector	"H"peak output current (P_W ≤ 2.5μs,f ≤ 15kHz)	(Note 2)	I_{OPH}	−1.5	A
	"L"peak output current (P_W ≤ 2.5μs,f ≤ 15kHz)	(Note 2)	I_{OPL}	+1.5	A
	Output voltage	(Ta ≤ 70°C)	V_O	35	V
		(Ta = 85°C)		24	
	Supply voltage	(Ta ≤ 70°C)	V_{CC}	35	V
		(Ta = 85°C)		24	
	Output voltage derating (Ta ≥ 70°C)		$\Delta V_O / \Delta Ta$	−0.73	V / °C
	Supply voltage derating (Ta ≥ 70°C)		$\Delta V_{CC} / \Delta Ta$	−0.73	V / °C
	Junction temperature		Tj	125	°C
Operating frequency		(Note 3)	f	25	kHz
Operating temperature range			T_{opr}	−20~85	°C
Storage temperature range			T_{stg}	−55~125	°C
Lead soldering temperature (10 s)		(Note 4)	T_{sol}	260	°C
Isolation voltage (AC, 1 min., R.H.≤ 60%)		(Note 5)	BV_S	2500	Vrms

Note 1: Pulse width P_W ≤ 1μs, 300pps

Note 2: Exporenential wavefom

Note 3: Exporenential wavefom, I_{OPH} ≤ −1.0A(≤ 2.5μs), I_{OPL} ≤ +1.0A(≤ 2.5μs)

Note 4: It is 2 mm or more from a lead root.

Note 5: Device considerd a two terminal device: Pins 1, 2, 3 and 4 shorted together, and pins 5, 6, 7 and 8 shorted together.

Note 6: A ceramic capacitor(0.1μF) should be connected from pin 8 to pin 5 to stabilize the operation of the high gain linear amplifier. Failure to provide the bypassing may impair the switching proparty. The total lead length between capacitor and coupler should not exceed 1cm.

Recommended Operating Conditions

Characteristic		Symbol	Min.	Typ.	Max.		Unit
Input current, on	(Note 7)	$I_{F(ON)}$	7	8	10		mA
Input voltage, off		$V_{F(OFF)}$	0	—	0.8		V
Supply voltage		V_{CC}	15	—	30	20	V
Peak output current		I_{OPH}/I_{OPL}	—	—	±0.5		A
Operating temperature		T_{opr}	−20	25	70	85	°C

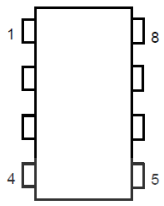
Note 7: Input signal rise time (fall time) < 0.5 μs.

Electrical Characteristics (Ta = −20~70°C, unless otherwise specified)

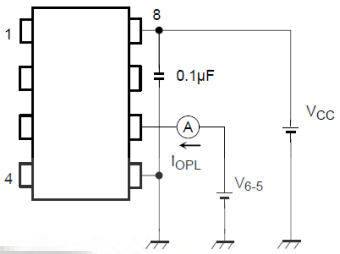
Characteristic		Symbol	Test Cir-cuit	Test Condition		Min.	Typ.*	Max.	Unit
Input forward voltage		V_F	—	I_F = 10 mA , Ta = 25°C			1.6	1.8	V
Temperature coefficient of forward voltage		$\Delta V_F / \Delta Ta$	—	I_F = 10 mA		—	−2.0	—	mV / °C
Input reverse current		I_R	—	V_R = 5V, Ta = 25°C			—	10	μA
Input capacitance		C_T	—	V = 0 , f = 1MHz , Ta = 25°C		—	45	250	pF
Output current	"H" level	I_{OPH}	3	V_{CC} = 30V (*1)	I_F = 10 mA V_{8-6} = 4V	−0.5	−1.5	—	A
	"L" level	I_{OPL}	2		I_F = 0 V_{6-5} = 2.5V	0.5	2	—	
Output voltage	"H" level	V_{OH}	4	V_{CC1} = +15V, V_{EE1} = −15V R_L = 200Ω, I_F = 5mA		11	12.8	—	V
	"L" level	V_{OL}	5	V_{CC1} = +15V, V_{EE1} = −15V R_L = 200Ω, V_F = 0.8V		—	−14.2	−12.5	
Supply current	"H" level	I_{CCH}	—	V_{CC} = 30V, I_F = 10mA Ta = 25°C		—	7	—	mA
				V_{CC} = 30V, I_F = 10mA		—	—	11	
	"L" level	I_{CCL}	—	V_{CC} = 30V, I_F = 0mA Ta = 25°C		—	7.5	—	
				V_{CC} = 30V, I_F = 0mA		—	—	11	
Threshold input current	"Output L→H"	I_{FLH}	—	V_{CC1} = +15V, V_{EE1} = −15V R_L = 200Ω, V_O > 0V		—	1.2	5	mA
Threshold input voltage	"Output H→L"	I_{FHL}	—	V_{CC1} = +15V, V_{EE1} = −15V R_L = 200Ω, V_O < 0V		0.8	—	—	V
Supply voltage		V_{CC}	—			10	—	35	V
Capacitance (input–output)		C_S	—	V_S = 0 , f = 1MHz Ta = 25• •		—	1.0	2.0	pF
Resistance(input–output)		R_S	—	V_S = 500V , Ta = 25°C R.H.≤ 60%		1×10^{12}	10^{14}	—	Ω

* All typical values are at Ta = 25°C (*1): Duration of I_O time ≤ 50μs

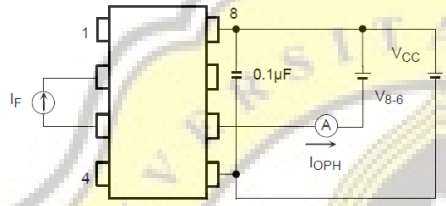
Test Circuit 1 :



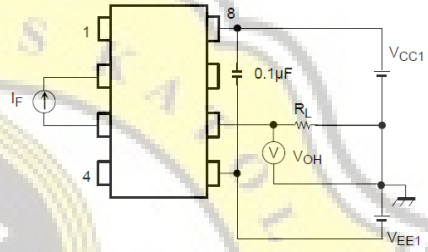
Test Circuit 2 : IOPL



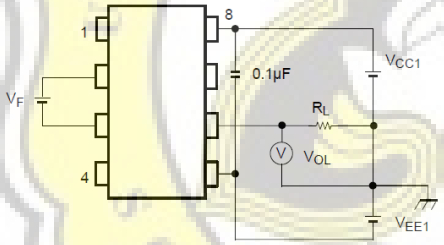
Test Circuit 3 : IOPH



Test Circuit 4 : VOH



Test Circuit 5 : V_{OL}



Data sheet IR2111

International
IOR Rectifier

Data Sheet No. PD60028-M

IR2111(S)&(PbF)

HALF-BRIDGE DRIVER

Features

- Floating channel designed for bootstrap operation
  Fully operational to +600V
  Tolerant to negative transient voltage
  dV/dt immune
- Gate drive supply range from 10 to 20V
- Undervoltage lockout for both channels
- CMOS Schmitt-triggered inputs with pull-down
- Matched propagation delay for both channels
- Internally set deadtime
- High side output in phase with input
- Also available LEAD-FREE

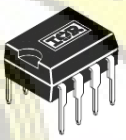
Product Summary

V_{OFFSET}	600V max.
I_O+/-	200 mA / 420 mA
V_{OUT}	10 - 20V
$t_{on/off}$ (typ.)	750 & 150 ns
Deadtime (typ.)	650 ns

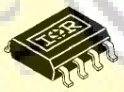
Description

The IR2111(S) is a high voltage, high speed power MOSFET and IGBT driver with dependent high and low side referenced output channels designed for half-bridge applications. Proprietary HVIC and latch immune CMOS technologies enable ruggedized monolithic construction. Logic input is compatible with standard CMOS outputs. The output drivers feature a high pulse current buffer stage designed for minimum driver cross-conduction. Internal deadtime is provided to avoid shoot-through in the output half-bridge. The floating channel can be used to drive an N-channel power MOSFET or IGBT in the high side configuration which operates up to 600 volts.

Packages

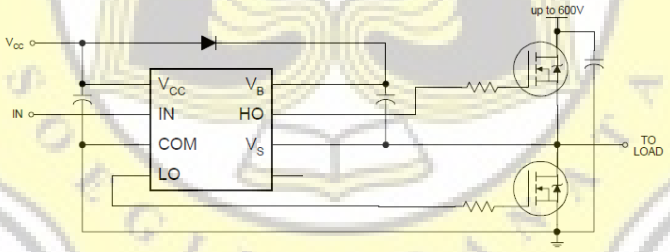


8-Lead PDIP



8-Lead SOIC

Typical Connection



(Refer to Lead Assignments for correct pin configuration). This/These diagram(s) show electrical connections only. Please refer to our Application Notes and DesignTips for proper circuit board layout.

Absolute Maximum Ratings

Absolute maximum ratings indicate sustained limits beyond which damage to the device may occur. All voltage parameters are absolute voltages referenced to COM. The thermal resistance and power dissipation ratings are measured under board mounted and still air conditions. Additional information is shown in figures 7 through 10.

Symbol	Definition		Min.	Max.	Units
V_B	High side floating supply voltage		-0.3	625	V
V_S	High side floating supply offset voltage		V_B - 25	V_B + 0.3	
V_{HO}	High side floating output voltage		V_S - 0.3	V_B + 0.3	
V_{CC}	Low side and logic fixed supply voltage		-0.3	25	
V_{LO}	Low side output voltage		-0.3	V_{CC} + 0.3	
V_{IN}	Logic input voltage		-0.3	V_{CC} + 0.3	
dV_S/dt	Allowable offset supply voltage transient (figure 2)		—	50	V/ns
P_D	Package power dissipation @ $T_A \leq +25°C$	(8 Lead PDIP)	—	1.0	W
		(8 lead SOIC)	—	0.625	
$RthJA$	Thermal resistance, junction to ambient	(8 lead PDIP)	—	125	°C/W
		(8 lead SOIC)	—	200	
T_J	Junction temperature		—	150	°C
T_S	Storage temperature		-55	150	
T_L	Lead temperature (soldering, 10 seconds)		—	300	

Recommended Operating Conditions

The input/output logic timing diagram is shown in figure 1. For proper operation the device should be used within the recommended conditions. The V_S offset rating is tested with all supplies biased at 15V differential.

Symbol	Definition	Min.	Max.	Units
V_B	High side floating supply absolute voltage	V_S + 10	V_S + 20	V
V_S	High side floating supply offset voltage	Note 1	600	
V_{HO}	High side floating output voltage	V_S	V_B	
V_{CC}	Low side and logic fixed supply voltage	10	20	
V_{LO}	Low side output voltage	0	V_{CC}	
V_{IN}	Logic input voltage	0	V_{CC}	
T_A	Ambient temperature	-40	125	°C

Note 1: Logic operational for V_S of -5 to +600V. Logic state held for V_S of -5V to $-V_{BS}$. (Please refer to the Design Tip DT97-3 for more details).

Dynamic Electrical Characteristics

V_{BIAS} (V_{CC}, V_{BS}) = 15V, C_L = 1000 pF and T_A = 25°C unless otherwise specified. The dynamic electrical characteristics are measured using the test circuit shown in figure 3.

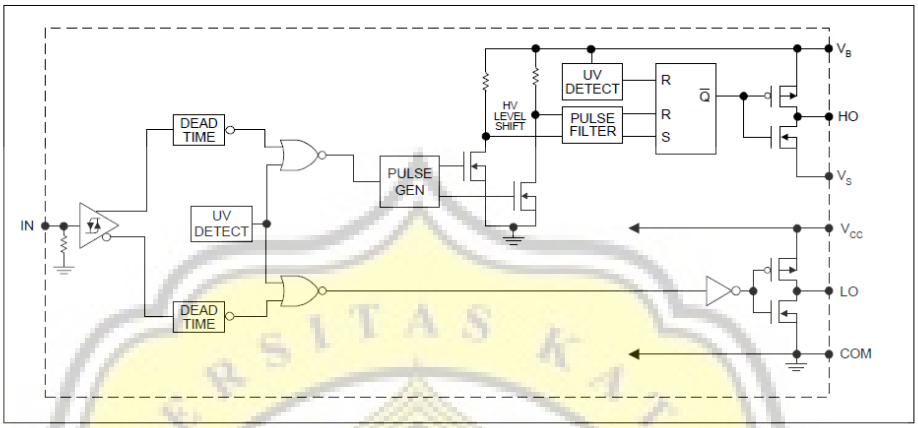
Symbol	Definition	Min.	Typ.	Max.	Units	Test Conditions
t_{on}	Turn-on propagation delay	550	750	950	ns	V_S = 0V
t_{off}	Turn-off propagation delay	—	150	180		V_S = 600V
t_r	Turn-on rise time	—	80	130		
t_f	Turn-off fall time	—	40	65		
DT	Deadtime, LS turn-off to HS turn-on & HS turn-off to LS turn-on	480	650	820		
MT	Delay matching, HS & LS turn-on/off	—	30	—		

Static Electrical Characteristics

V_{BIAS} (V_{CC}, V_{BS}) = 15V and T_A = 25°C unless otherwise specified. The V_{IN}, V_{TH} and I_{IN} parameters are referenced to COM. The V_O and I_O parameters are referenced to COM and are applicable to the respective output leads: HO or LO.

Symbol	Definition	Min.	Typ.	Max.	Units	Test Conditions
V_{IH}	Logic "1" input voltage for HO & logic "0" for LO	6.4	—	—	V	V_{CC} = 10V
		9.5	—	—		V_{CC} = 15V
		12.6	—	—		V_{CC} = 20V
V_{IL}	Logic "0" input voltage for HO & logic "1" for LO	—	—	3.8		V_{CC} = 10V
		—	—	6.0		V_{CC} = 15V
		—	—	8.3		V_{CC} = 20V
V_{OH}	High level output voltage, V_{BIAS} - V_O	—	—	100	mV	I_O = 0A
V_{OL}	Low level output voltage, V_O	—	—	100		I_O = 0A
I_{LK}	Offset supply leakage current	—	—	50	µA	V_B = V_S = 600V
I_{QBS}	Quiescent V_{BS} supply current	—	50	100		V_{IN} = 0V or V_{CC}
I_{QCC}	Quiescent V_{CC} supply current	—	70	180		V_{IN} = 0V or V_{CC}
I_{IN+}	Logic "1" input bias current	—	30	50		V_{IN} = V_{CC}
I_{IN-}	Logic "0" input bias current	—	—	1.0		V_{IN} = 0V
V_{BSUV+}	V_{BS} supply undervoltage positive going threshold	7.6	8.6	9.6	V	
V_{BSUV-}	V_{BS} supply undervoltage negative going threshold	7.2	8.2	9.2		
V_{CCUV+}	V_{CC} supply undervoltage positive going threshold	7.6	8.6	9.6		
V_{CCUV-}	V_{CC} supply undervoltage negative going threshold	7.2	8.2	9.2		
I_{O+}	Output high short circuit pulsed current	200	250	—	mA	V_O = 0V, V_{IN} = V_{CC} PW ≤ 10 µs
I_{O-}	Output low short circuit pulsed current	420	500	—		V_O = 15V, V_{IN} = 0V PW ≤ 10 µs

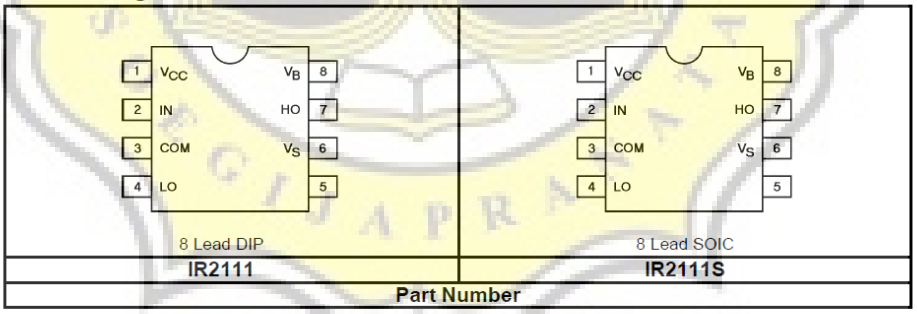
Functional Block Diagram



Lead Definitions

Symbol	Description
IN	Logic input for high side and low side gate driver outputs (HO & LO), in phase with HO
V_B	High side floating supply
HO	High side gate drive output
V_S	High side floating supply return
V_{CC}	Low side and logic fixed supply
LO	Low side gate drive output
COM	Low side return

Lead Assignments



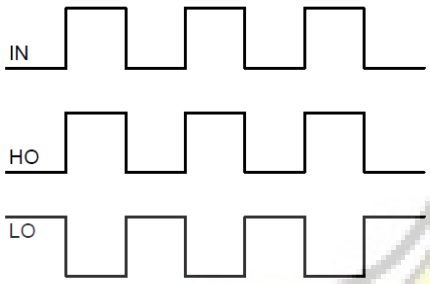


Figure 1. Input/Output Timing Diagram

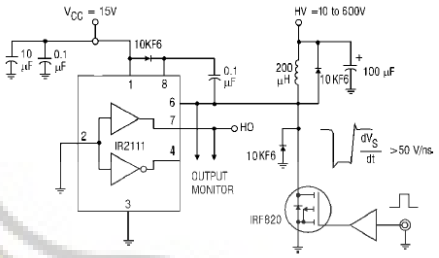


Figure 2. Floating Supply Voltage Transient Test Circuit

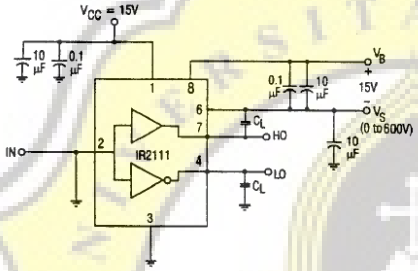


Figure 3. Switching Time Test Circuit

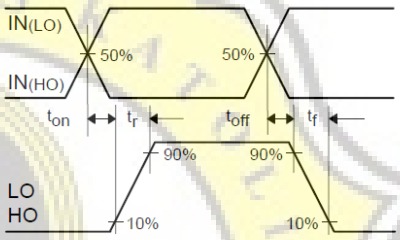


Figure 4. Switching Time Waveform Definition

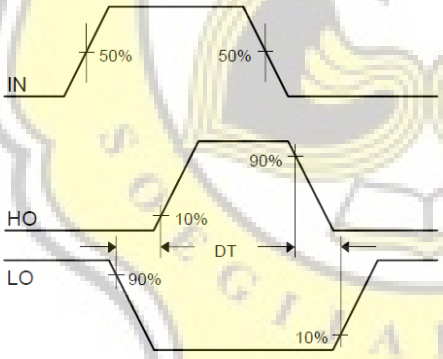


Figure 5. Deadtime Waveform Definitions

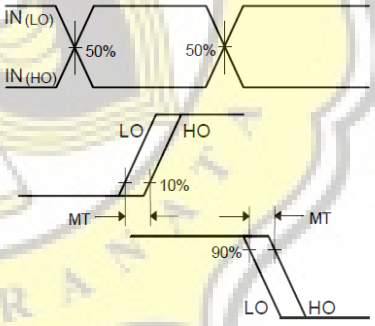


Figure 6. Delay Matching Waveform Definitions

Data sheet IR460

FAIRCHILD SEMICONDUCTOR®

IRFP460

Data Sheet **January 2002**

20A, 500V, 0.270 Ohm, N-Channel Power MOSFET

This N-Channel enhancement mode silicon gate power field effect transistor is an advanced power MOSFET designed, tested, and guaranteed to withstand a specified level of energy in the breakdown avalanche mode of operation. All of these power MOSFETs are designed for applications such as switching regulators, switching convertors, motor drivers, relay drivers, and drivers for high power bipolar switching transistors requiring high speed and low gate drive power. These types can be operated directly from integrated circuits.

Formerly developmental type TA17465.

Ordering Information

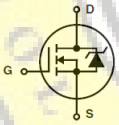
PART NUMBER	PACKAGE	BRAND
IRFP460	TO-247	IRFP460

NOTE: When ordering, use the entire part number.

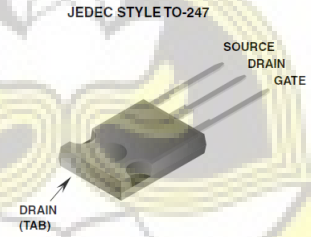
Features

- 20A, 500V
- $r_{DS(ON)} = 0.270\Omega$
- Single Pulse Avalanche Energy Rated
- SOA is Power Dissipation Limited
- Nanosecond Switching Speeds
- Linear Transfer Characteristics
- High Input Impedance
- Related Literature
  - TB334 “Guidelines for Soldering Surface Mount Components to PC Boards”

Symbol



Packaging



Absolute Maximum Ratings $T_C = 25^oC$, Unless Otherwise Specified

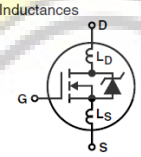
		IRFP460	UNITS
Drain to Source Voltage (Note 1)	V_{DS}	500	V
Drain to Gate Voltage (R_{GS} = 20kΩ) (Note 1)	V_{DGR}	500	V
Continuous Drain Current	I_D	20	A
$T_C = 100^oC$	I_D	12	A
Pulsed Drain Current (Note 3)	I_{DM}	80	A
Gate to Source Voltage	V_{GS}	±20	V
Maximum Power Dissipation	P_D	250	W
Linear Derating Factor		2.0	$W/^oC$
Single Pulse Avalanche Energy Rating (Note 4)	E_{AS}	960	mJ
Operating and Storage Temperature	T_J, T_{STG}	-55 to 150	^oC
Maximum Temperature for Soldering			
Leads at 0.063in (1.6mm) from Case for 10s	T_L	300	^oC
Package Body for 10s, See Techbrief 334	T_{pkg}	260	^oC

CAUTION: Stresses above those listed in "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress only rating and operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied.

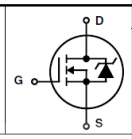
NOTE:

1. $T_J = 25^oC$ to $T_J = 125^oC$.

Electrical Specifications $T_C = 25^oC$, Unless Otherwise Specified

PARAMETER	SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNITS
Drain to Source Breakdown Voltage	BV_{DSS}	I_D = 250µA, V_{GS} = 0V (Figure 10)	500	-	-	V
Gate Threshold Voltage	$V_{GS(TH)}$	$V_{GS} = V_{DS}$, I_D = 250µA	2	-	4	V
Zero Gate Voltage Drain Current	I_{DSS}	V_{DS} = Rated BV_{DSS}, V_{GS} = 0V	-	-	25	µA
		V_{DS} = 0.8 x Rated BV_{DSS}, V_{GS} = 0V, $T_J = 125^oC$	-	-	250	µA
On-State Drain Current (Note 2)	$I_{D(ON)}$	$V_{DS} > I_{D(ON)} \times r_{DS(ON)MAX}$, V_{GS} = 10V	20	-	-	A
Gate to Source Leakage Current	I_{GSS}	V_{GS} = ±20V	-	-	±100	nA
Drain to Source On Resistance (Note 2)	$r_{DS(ON)}$	I_D = 11A, V_{GS} = 10V (Figures 8, 9)	-	0.24	0.27	Ω
Forward Transconductance (Note 2)	g_{fs}	$V_{DS} \geq 50V$, $I_{DS} > 11A$ (Figure 12)	13	19	-	S
Turn-On Delay Time	$t_{d(ON)}$	V_{DD} = 250V, I_D = 21A, R_{GS} = 4.3Ω, R_D = 12Ω, V_{GS} = 10V MOSFET Switching Times are Essentially Independent of Operating Temperature	-	23	35	ns
Rise Time	t_r		-	81	120	ns
Turn-Off Delay Time	$t_{d(OFF)}$		-	85	130	ns
Fall Time	t_f		-	65	98	ns
Total Gate Charge (Gate to Source + Gate-Drain)	$Q_{g(TOT)}$	V_{GS} = 10V, I_D = 21A, V_{DS} = 0.8 x Rated BV_{DSS}, $I_{G(REF)}$ = 1.5mA (Figure 14). Gate Charge is Essentially Independent of OperatingTemperature	-	120	190	nC
Gate to Source Charge	Q_{gs}		-	18	-	nC
Gate to Drain "Miller" Charge	Q_{gd}		-	62	-	nC
Input Capacitance	C_{ISS}	V_{DS} = 25V, V_{GS} = 0V, f = 1MHz (Figure 10)	-	4100	-	pF
Output Capacitance	C_{OSS}		-	480	-	pF
Reverse Transfer Capacitance	C_{RSS}		-	84	-	pF
Internal Drain Inductance	L_D	Measured from the Drain Lead, 6mm (0.25in) from Package to Center of Die. Modified MOSFET Symbol Showing the Internal Device Inductances	-	5.0	-	nH
Internal Source Inductance	L_S	Measured from the Source Lead, 6mm (0.25in) from Header to Source Bonding Pad. 	-	13	-	nH
Thermal Resistance Junction to Case	$R_{\theta JC}$		-	-	0.50	$^oC/W$
Thermal Resistance Junction to Ambient	$R_{\theta JA}$	Free Air Operation	-	-	30	$^oC/W$

Source to Drain Diode Specifications

PARAMETER	SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNITS
Continuous Source to Drain Current	I_{SD}	Modified MOSFET Symbol Showing the Integral Reverse P-N Junction Rectifier 	-	-	20	A
Pulse Source to Drain Current (Note 3)	I_{SDM}		-	-	80	A
Source to Drain Diode Voltage (Note 2)	V_{SD}	$T_J = 25^oC$, $I_{SD} = 21A$, $V_{GS} = 0V$ (Figure 13)	-	-	1.8	V
Reverse Recovery Time	t_{rr}	$T_J = 25^oC$, $I_{SD} = 21A$, $dI_{SD}/dt = 100A/\mu s$	280	580	1200	ns
Reverse Recovery Charge	Q_{RR}	$T_J = 25^oC$, $I_{SD} = 21A$, $dI_{SD}/dt = 100A/\mu s$	3.8	8.1	18	µC

NOTES:

2. Pulse test: pulse width ≤ 300µs, duty cycle ≤ 2%.
3. Repetitive rating: pulse width limited by Max junction temperature. See Transient Thermal Impedance curve (Figure 3).
4. $V_{DD} = 50V$, starting $T_J = 25^oC$, $L = 4.3mH$, $R_{GS} = 25\Omega$, Peak $I_{AS} = 20A$.

Typical Performance Curves Unless Otherwise Specified

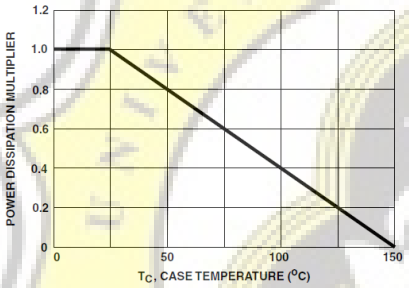


FIGURE 1. NORMALIZED POWER DISSIPATION vs CASE TEMPERATURE

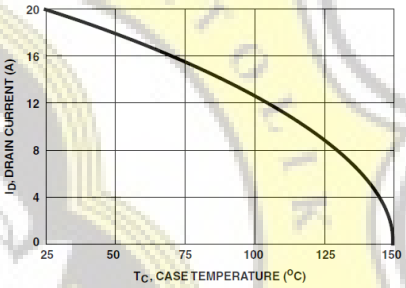


FIGURE 2. MAXIMUM CONTINUOUS DRAIN CURRENT vs CASE TEMPERATURE

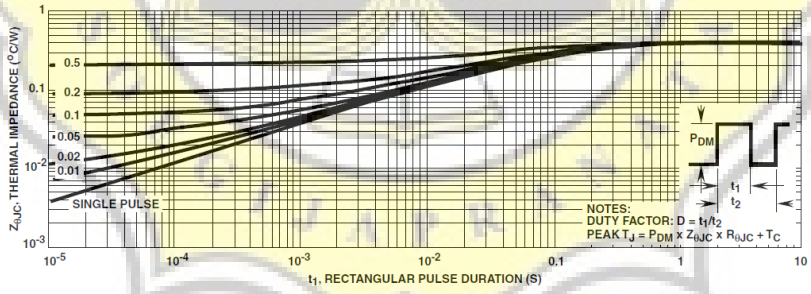


FIGURE 3. MAXIMUM TRANSIENT THERMAL IMPEDANCE

Typical Performance Curves Unless Otherwise Specified (Continued)

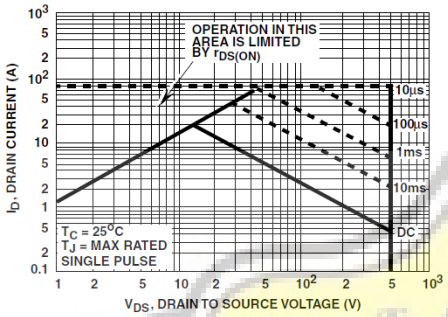


FIGURE 4. FORWARD BIAS SAFE OPERATING AREA

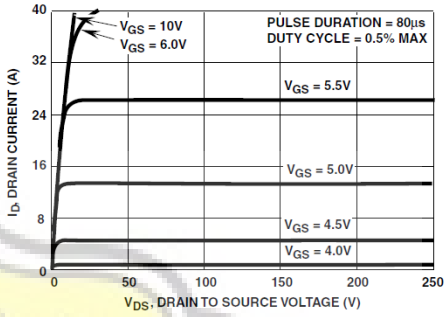


FIGURE 5. OUTPUT CHARACTERISTICS

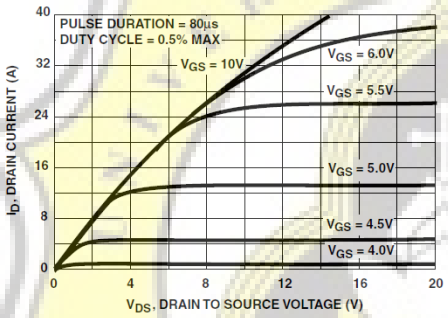


FIGURE 6. SATURATION CHARACTERISTICS

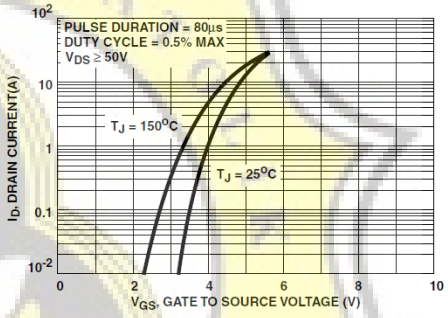


FIGURE 7. TRANSFER CHARACTERISTICS

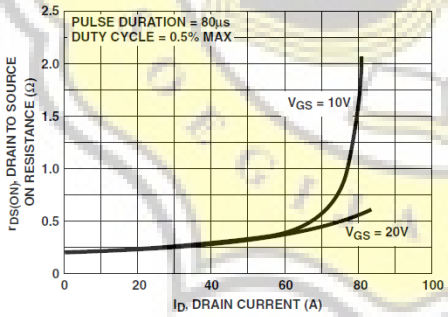


FIGURE 8. DRAIN TO SOURCE ON RESISTANCE vs GATE VOLTAGE AND DRAIN CURRENT

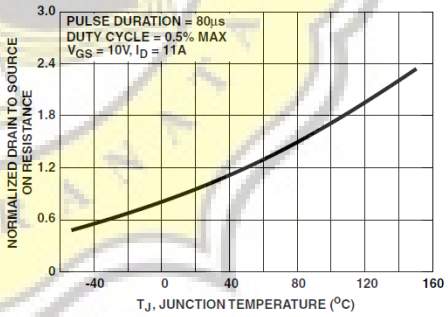


FIGURE 9. NORMALIZED DRAIN TO SOURCE ON RESISTANCE vs JUNCTION TEMPERATURE

Test Circuits and Waveforms

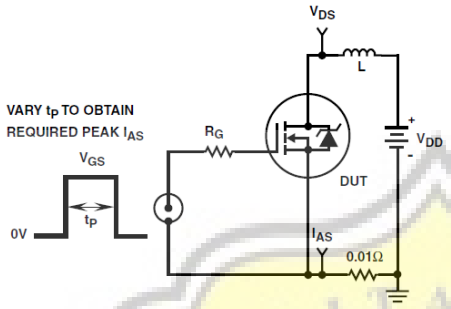


FIGURE 15. UNCLAMPED ENERGY TEST CIRCUIT

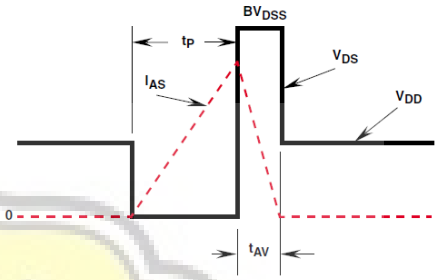


FIGURE 16. UNCLAMPED ENERGY WAVEFORMS

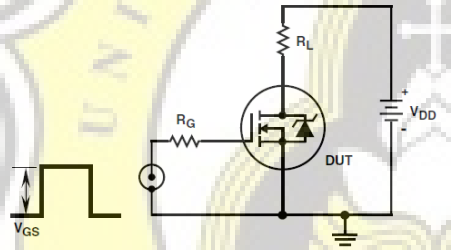


FIGURE 17. SWITCHING TIME TEST CIRCUIT

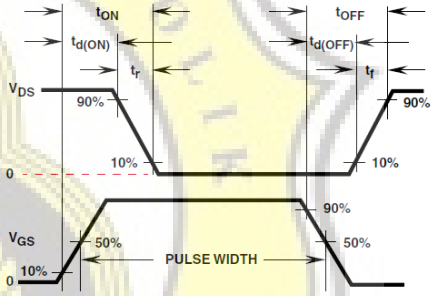


FIGURE 18. RESISTIVE SWITCHING WAVEFORMS

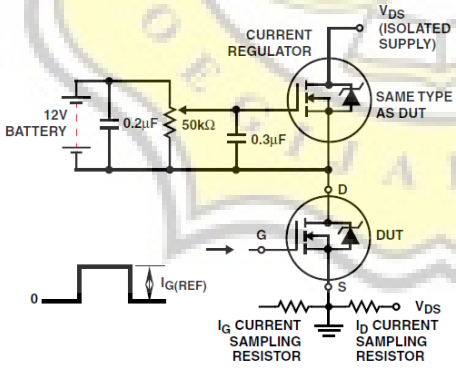


FIGURE 19. GATE CHARGE TEST CIRCUIT

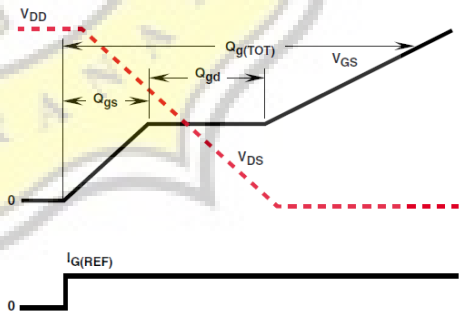


FIGURE 20. GATE CHARGE WAVEFORMS